

Hydrogen Peroxide, 30%
Electronic Grade
(Stabilized)



Material No.: 2204-01
Batch No.: 0000014470
Manufactured Date: 2012/08/10
Expiration Date: 2014/02/08


Certificate of Analysis

Test	Specification	Result
Assay (H ₂ O ₂)	30.0 – 32.0 %	31.5
Color (APHA)	<= 10	5
Free Acid (µeq/g)	<= 0.2	< 0.1
Residue after Evaporation	<= 15 ppm	< 5
Ammonium (NH ₄)	<= 3 ppm	< 3
Chloride (Cl)	<= 2 ppm	< 1
Nitrate (NO ₃)	<= 2 ppm	< 2
Phosphate (PO ₄)	<= 2 ppm	< 1
ACS – Sulfate (SO ₄)	<= 5 ppm	< 3
Trace Impurities – Aluminum (Al)	<= 200.0 ppb	< 5.0
Trace Impurities – Antimony (Sb)	<= 10.0 ppb	< 1.0
Trace Impurities – Arsenic (As)	<= 10.0 ppb	< 2.0
Arsenic and Antimony (as As)	<= 10 ppb	< 10
Trace Impurities – Barium (Ba)	<= 20.0 ppb	< 1.0
Trace Impurities – Beryllium (Be)	<= 10.0 ppb	< 1.0
Trace Impurities – Bismuth (Bi)	<= 20.0 ppb	< 10.0
Trace Impurities – Boron (B)	<= 10.0 ppb	< 5.0
Trace Impurities – Cadmium (Cd)	<= 10.0 ppb	< 1.0
Trace Impurities – Calcium (Ca)	<= 50.0 ppb	< 1.0
Trace Impurities – Chromium (Cr)	<= 20.0 ppb	< 1.0
Trace Impurities – Cobalt (Co)	<= 10.0 ppb	< 1.0
Trace Impurities – Copper (Cu)	<= 10.0 ppb	< 1.0
Trace Impurities – Gallium (Ga)	<= 20.0 ppb	< 1.0
Trace Impurities – Germanium (Ge)	<= 10.0 ppb	< 10.0


Test	Specification	Result
Trace Impurities – Gold (Au)	<= 10.0 ppb	< 5.0
Heavy Metals (as Pb)	<= 500 ppb	< 250
Trace Impurities – Iron (Fe)	<= 50.0 ppb	< 1.0
Trace Impurities – Lead (Pb)	<= 10.0 ppb	< 10.0
Trace Impurities – Lithium (Li)	<= 10.0 ppb	< 1.0
Trace Impurities – Magnesium (Mg)	<= 10.0 ppb	< 1.0
Trace Impurities – Manganese (Mn)	<= 10.0 ppb	< 1.0
Trace Impurities – Molybdenum (Mo)	<= 10.0 ppb	< 5.0
Trace Impurities – Nickel (Ni)	<= 10.0 ppb	< 5.0
Trace Impurities – Niobium (Nb)	<= 10.0 ppb	< 1.0
Trace Impurities – Potassium (K)	<= 600.0 ppb	209.0
Trace Impurities – Silicon (Si)	<= 100.0 ppb	< 10.0
Trace Impurities – Silver (Ag)	<= 10.0 ppb	< 1.0
Trace Impurities – Sodium (Na)	<= 500.0 ppb	< 5.0
Trace Impurities – Strontium (Sr)	<= 10.0 ppb	< 1.0
Trace Impurities – Tantalum (Ta)	<= 10.0 ppb	< 5.0
Trace Impurities – Thallium (Tl)	<= 50.0 ppb	< 5.0
Trace Impurities – Tin (Sn)	<= 1000.0 ppb	299.0
Trace Impurities – Titanium (Ti)	<= 10.0 ppb	< 1.0
Trace Impurities – Vanadium (V)	<= 10.0 ppb	< 1.0
Trace Impurities – Zinc (Zn)	<= 50.0 ppb	< 1.0
Trace Impurities – Zirconium (Zr)	<= 10.0 ppb	< 1.0

For Microelectronic Use

Country of Origin: US
Packaging Site: Paris Mfg Ctr & DC



Phillipsburg, NJ 9001:2008, 14001:2004
 Paris, KY 9001:2008
 Mexico City, Mexico 9001:2008
 Deventer, The Netherlands 9001:2008, 14001:2004, 13485:2003
 Gliwice, Poland 9001:2008, 17025:2005
 Selangor, Malaysia 9001:2008
 Dehradun, India, 9001:2008, 14001:2004, 13485:2003
 Mumbai, India, 9001:2008, 17025:2005
 Panoli, India 9001:2008



Richard M Siberski
 Global Director of Quality Assurance

For questions on this Certificate of Analysis please contact Technical Services at 855.282.6867 or +1.610.573.2600
 Avantor™ Performance Materials Inc.
 3477 Corporate Parkway, Suite #200, Center Valley, PA 18034, U.S.A. Phone: 610.573.2600 . Fax: 610.573.2610